	Experiment title: USAXS studies of the grain-growth kinetics in nanocrystalline and amorphous Chromium.	Experiment number:
ESRF		HS 1706
Beamline:	Date of experiment:	Date of report:
ID-02A	06/07 - 09/07/2002	19/12/2002
Shifts: 8	Local contact(s): Volker Urban	Received at ESRF:
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## **Report:**

The microstructural studies of electrodeposited nanocrystalline n-Ni, n-Co [1] and n-Cr [2] by small angle neutron scattering (SANS) have shown fractal-type density correlations. Such fractal microstructures contribute to a small angle scattering (SAS) signal which does not obey the Porod law, but show a power-law behaviour  $I(Q) \propto Q^{-\alpha}$ , where the exponent  $\alpha$  has values between 2 and 4.

On the other hand, many nanocrystalline metallic materials undergo a grain growth process during annealing [4-5]. The changes of the crystalline microstructure of n-Cr were already studied by time dependent SR diffraction at the beamline ID-31 [6]. Diffraction measurements provided information about increase of the average grain size [6]. In the present study, the microstructure of n-Cr and amorphous Cr (am-Cr) was studied by time dependent SAXS measurements performed during annealing at several temperatures.

The SAXS signal measured at RT before annealing have shown a power-law behaviour in a similar way as it was observed in earlier SANS studies [1]. During annealing we observe an increase of the exponent  $\alpha$  towards a value of 4 which corresponds to a Porod law describing SAS on smooth objects. The resulting time dependence of the exponent  $\alpha$  obtained for different temperatures is shown in Fig. 1.



Fig.1 Time dependence of the power-law exponent  $\alpha$  obtained from time-dependent SAXS measurements performed during annealing of nanocrystalline (n-Cr) at 250 °C and 400 °C. The lines are shown to guide-the-eye.

One can see that with annealing at 400 <sup>o</sup>C the exponent appraoches very close to the Porod law value of 4. Annealing at 250 <sup>o</sup>C also increases the value of the power-law exponent, but it saturates at a value much smaller than 4. Further data analysis is in progress.

This work was supported by the European Community Marie Curie Fellowship performed at I.L.L. by one of us (RP) under contract HPMF-CT-2000-01002. This work was partially supported by Committee for Scientific Research (Poland).

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